

<b>Notice of References Cited</b>	Application/Control No. 10/747,644	Applicant(s)/Patent Under Reexamination DEMIR ET AL.	
	Examiner Eva Yi Zheng	Art Unit 2611	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,549,763	04-2003	Imai et al.	455/249.1
*	C	US-2004/0176055	09-2004	Vepsalainen et al.	455/130
	D	US-			
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	J	US-			
	K	US-			
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**NON-PATENT DOCUMENTS**

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